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Ishii

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(54) LIGHT WAVE DISTANCE MEASURING THEODOLITE

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (10) Cl.** **10-04**
(52) **U.S. Cl.**
USPC **D10/66**; D10/69; D10/70
(58) **Field of Classification Search**
CPC G01C 15/00; G01C 15/06; G01C 15/002; G01C 21/16; G01C 21/165; G01C 25/00; G01C 1/04; G01C 3/08; G01S 19/49; G01S 19/51; G01S 5/12; G01S 5/16; G01S 17/10; G01S 17/42; G01S 7/4818; G01S 33/21; G01B 11/26
USPC .... D10/66, 69, 70; 33/276, 277, 281, 285, 33/286, 290, 291–299, DIG. 21; 340/539, 340/825.36, 825.46, 825.49; 356/5.15, 356/4.01, 5.01, 4.05, 5.05–5.09, 5.12, 28.5, 356/345, 375, 3.01, 128–155, 399–400; 385/83, 97–99, 134–139; 264/1.24–1.25
See application file for complete search history.

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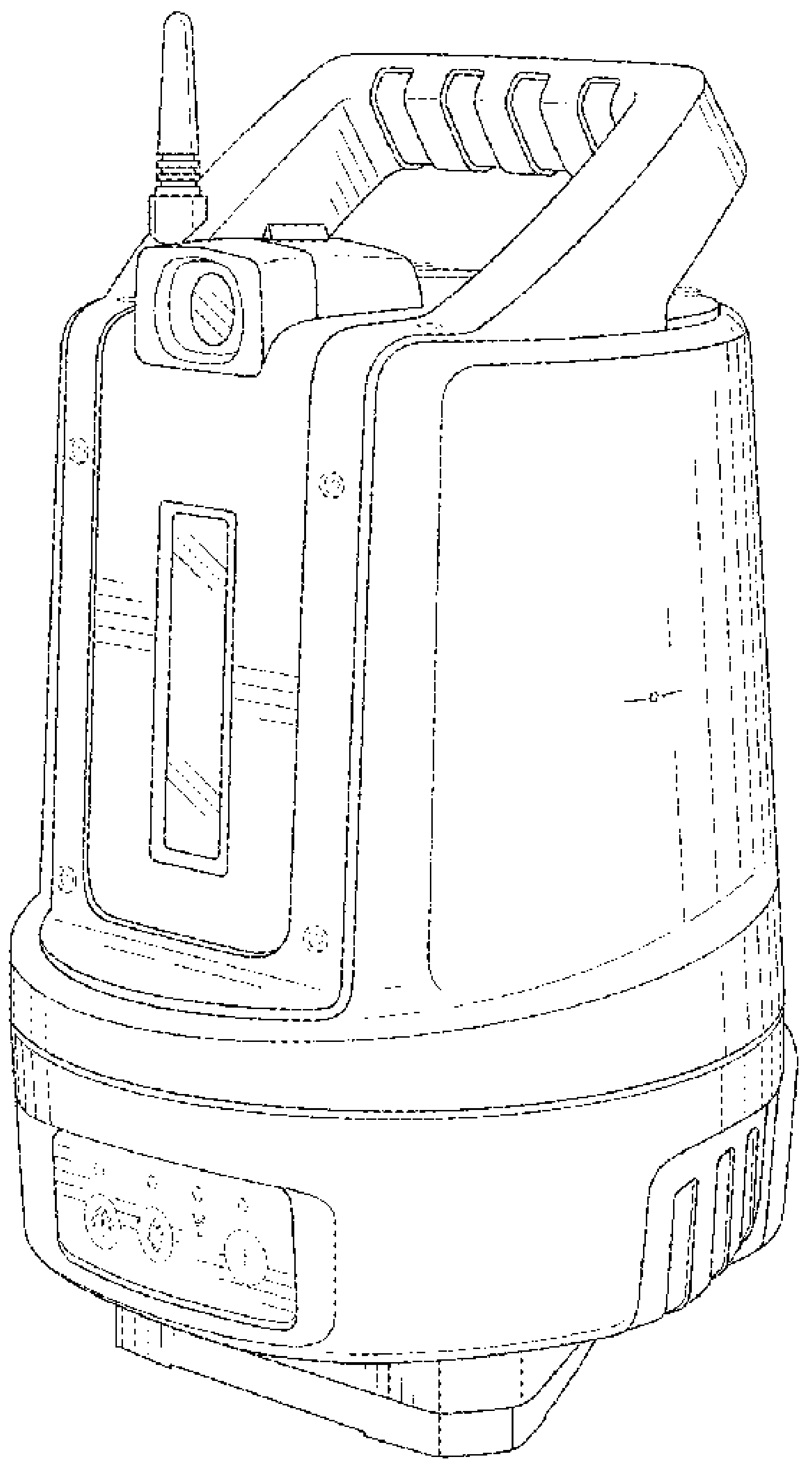
(57) **CLAIM**

The ornamental design for a light wave distance measuring theodolite, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a light wave distance measuring theodolite;
FIG. **2** is a front view thereof;
FIG. **3** is a top view thereof;
FIG. **4** is a right-side view thereof;
FIG. **5** is a left-side view thereof;
FIG. **6** is a rear view thereof; and,
FIG. **7** is a bottom view thereof.
The broken lines depict environmental subject matter only and form no part of the claimed design.
The claimed light wave distance measuring theodolite is for use in measuring distances and angles, wherein measurement data and architectonics data can also be transmitted and received to other instruments.

1 Claim, 7 Drawing Sheets



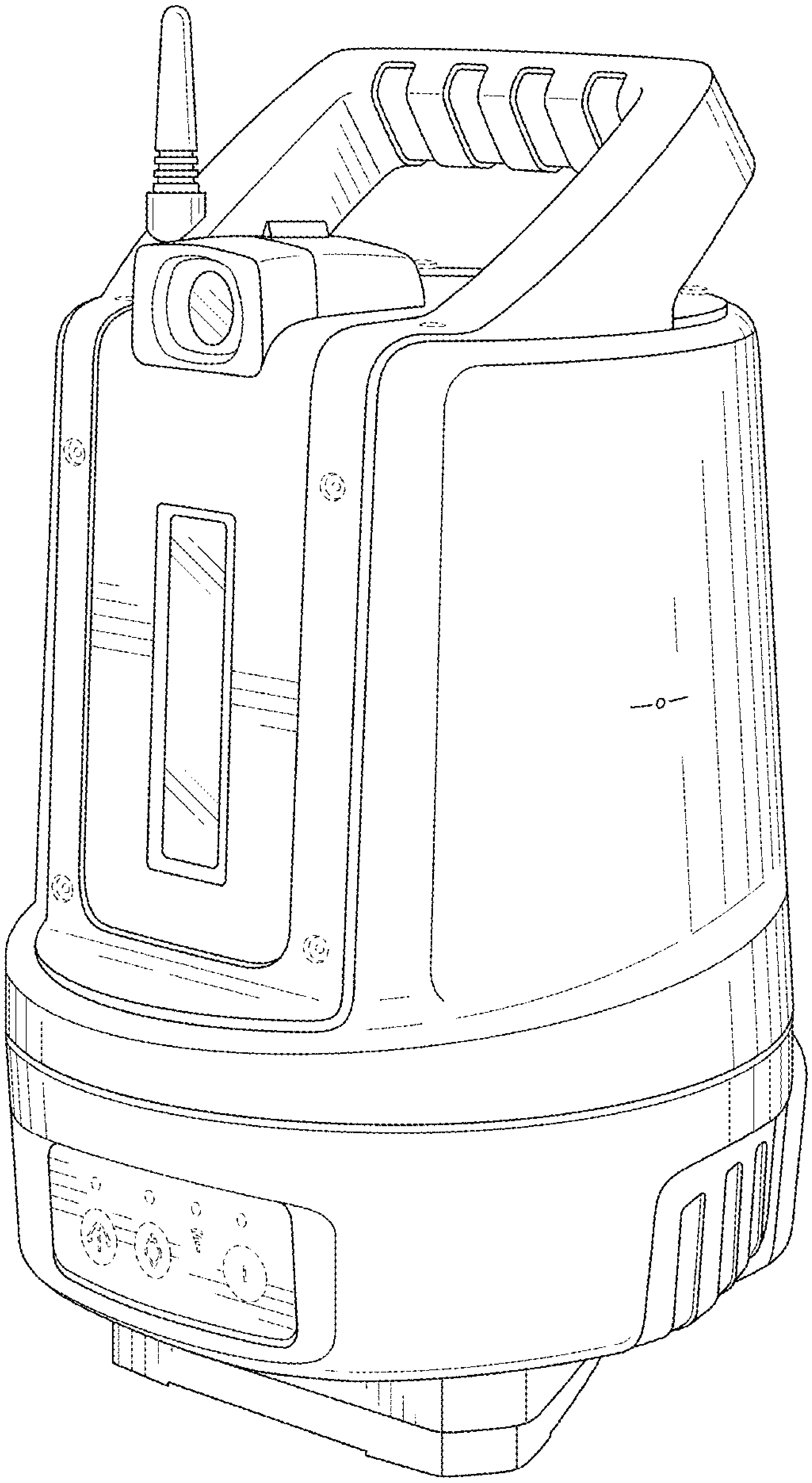


FIG. 1

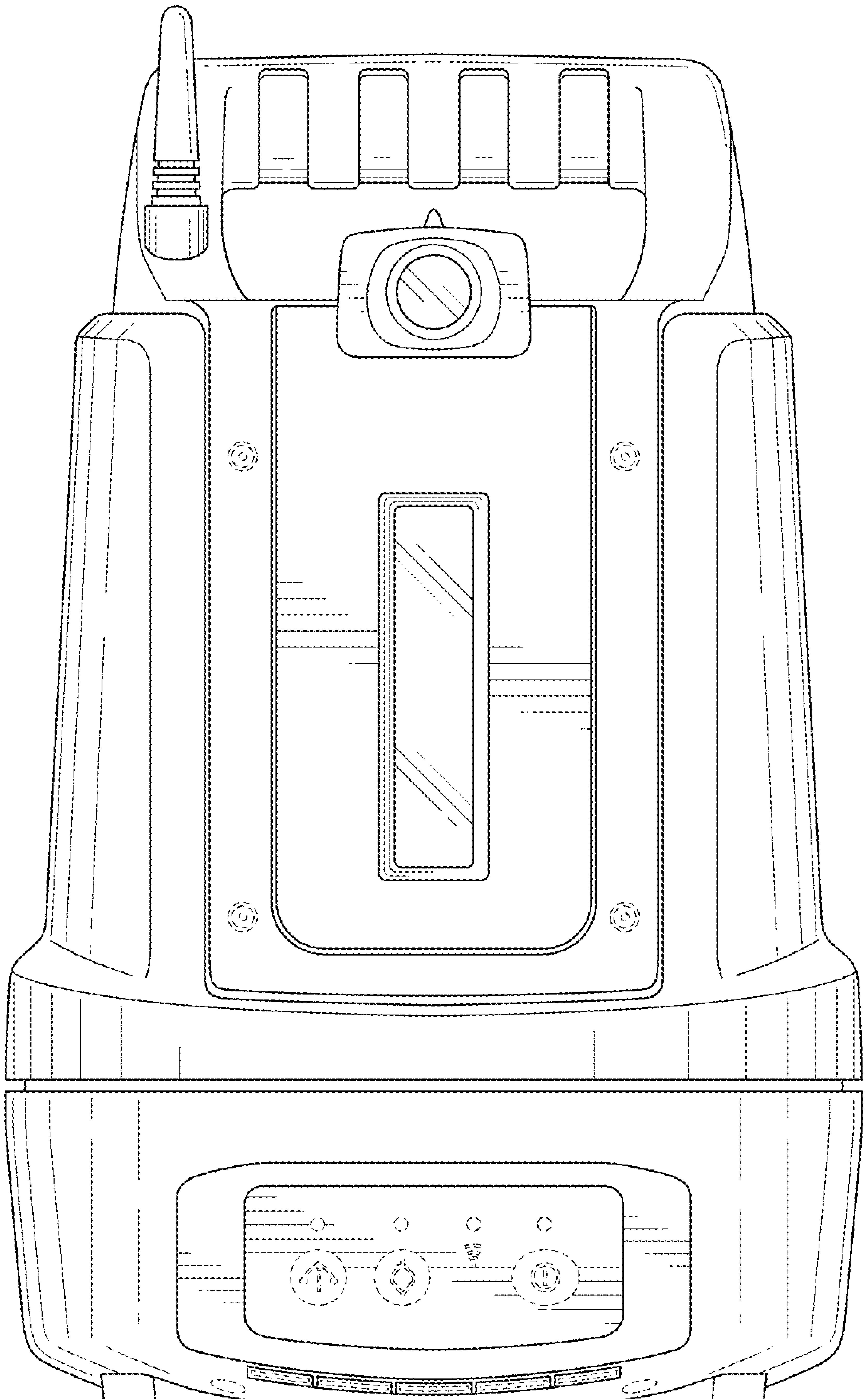


FIG. 2

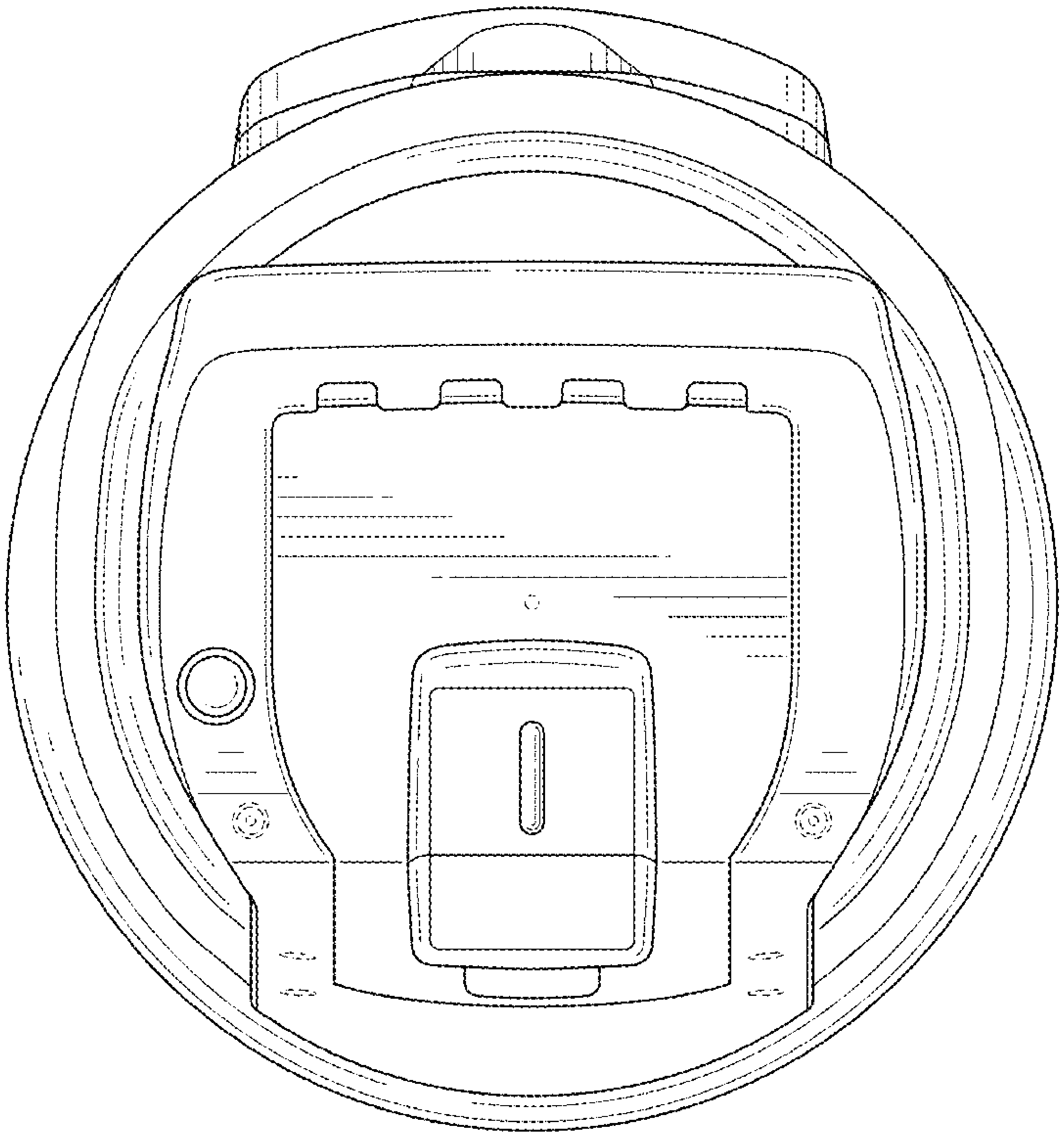


FIG. 3

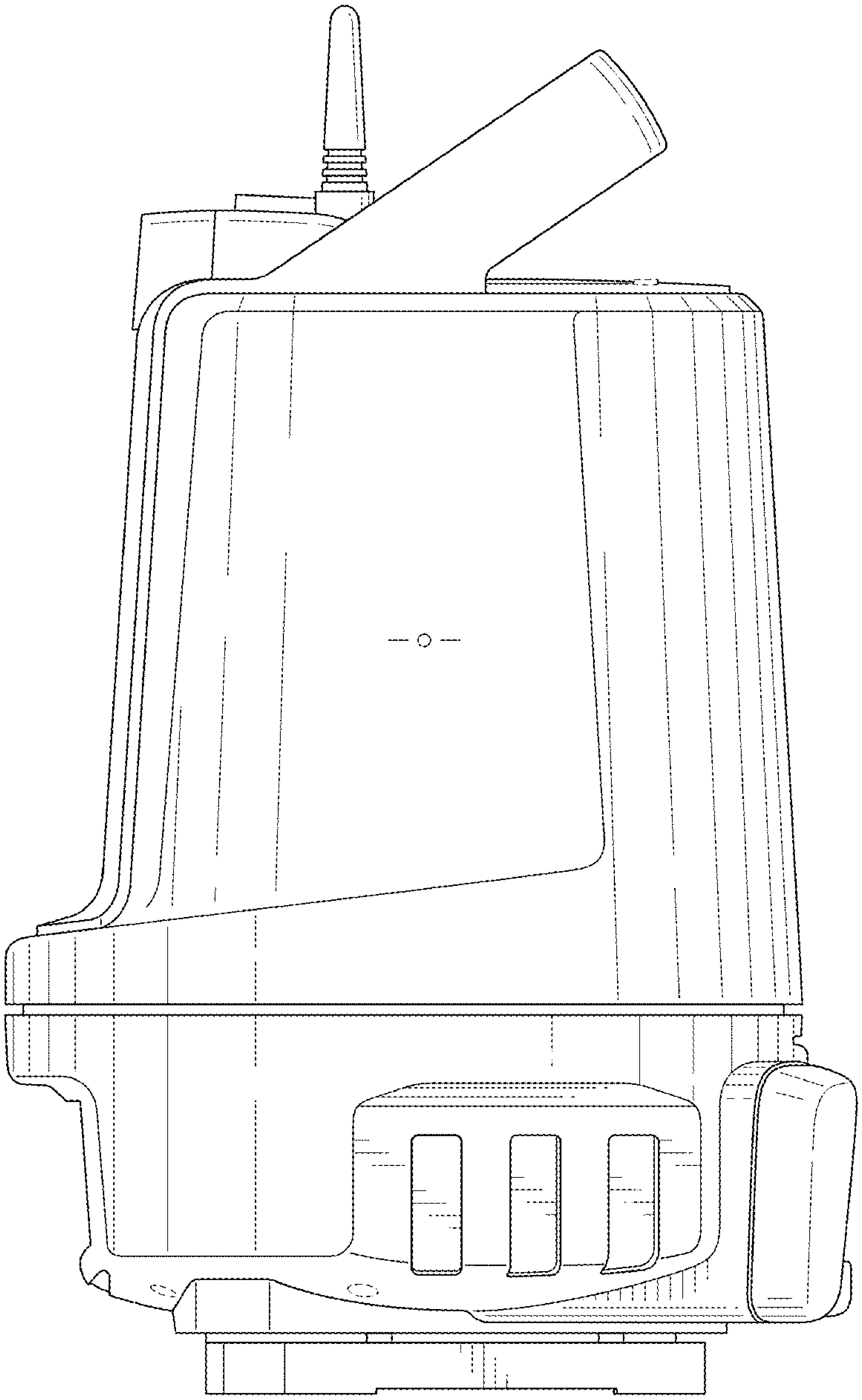


FIG. 4

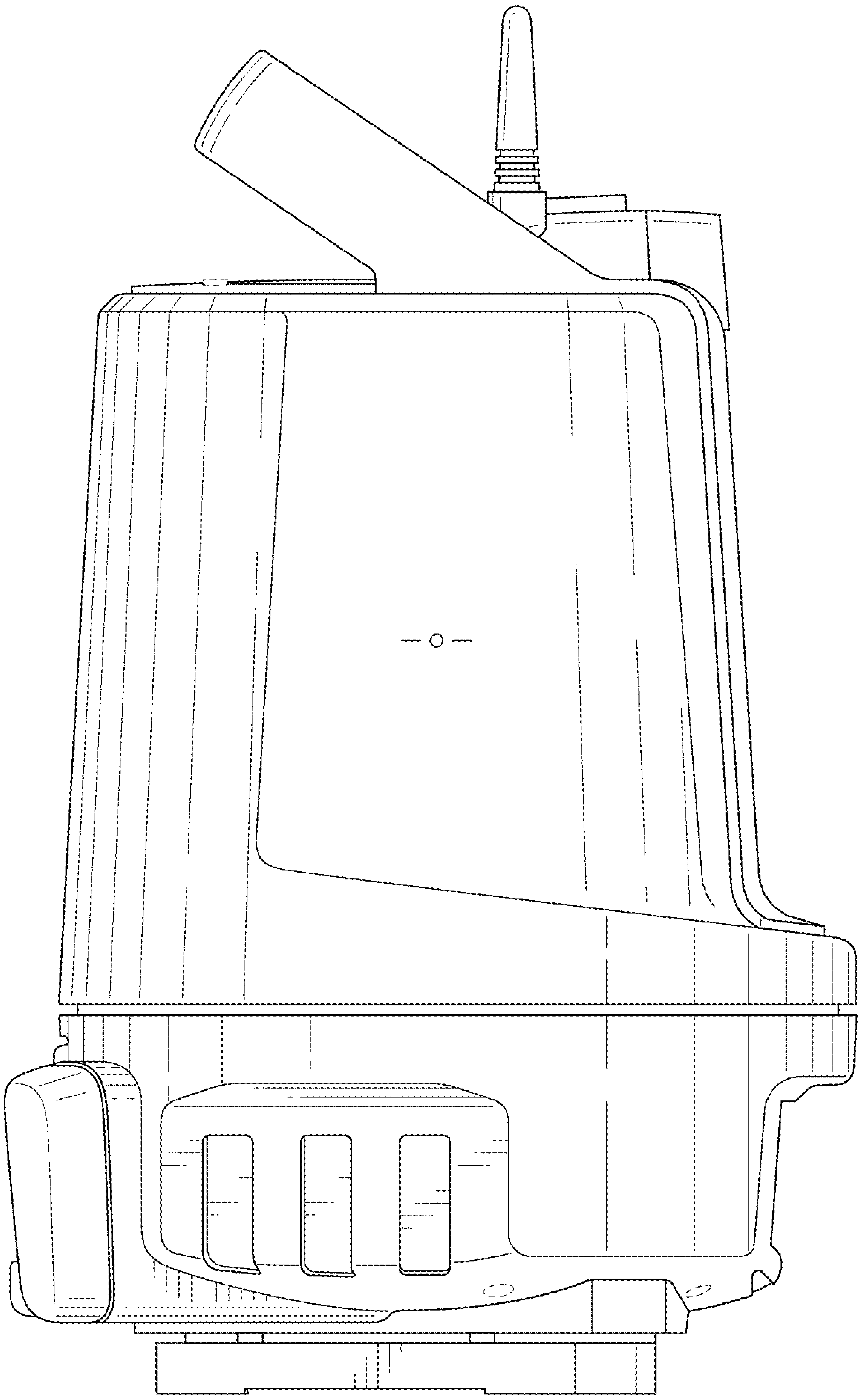


FIG. 5

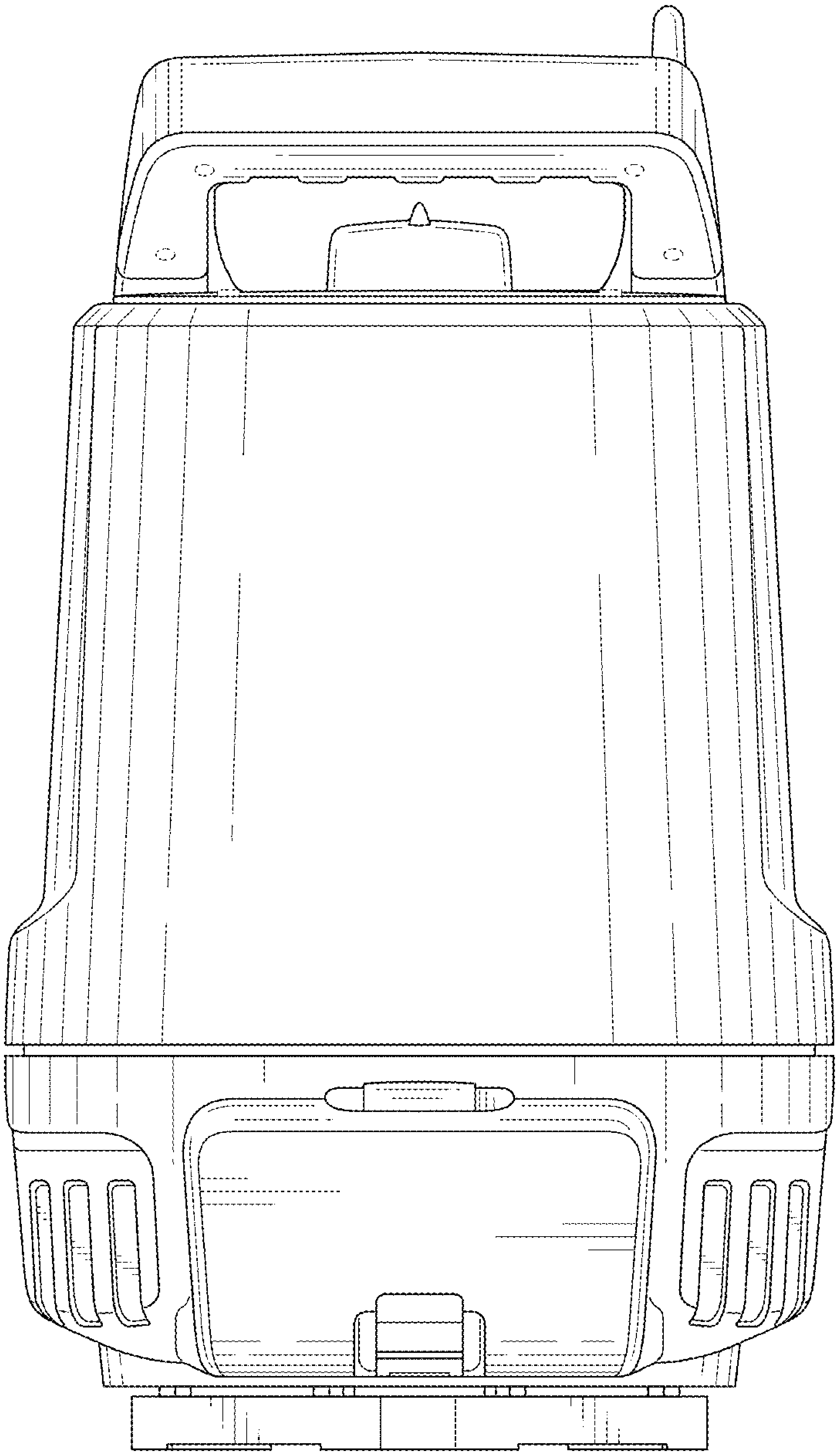


FIG. 6

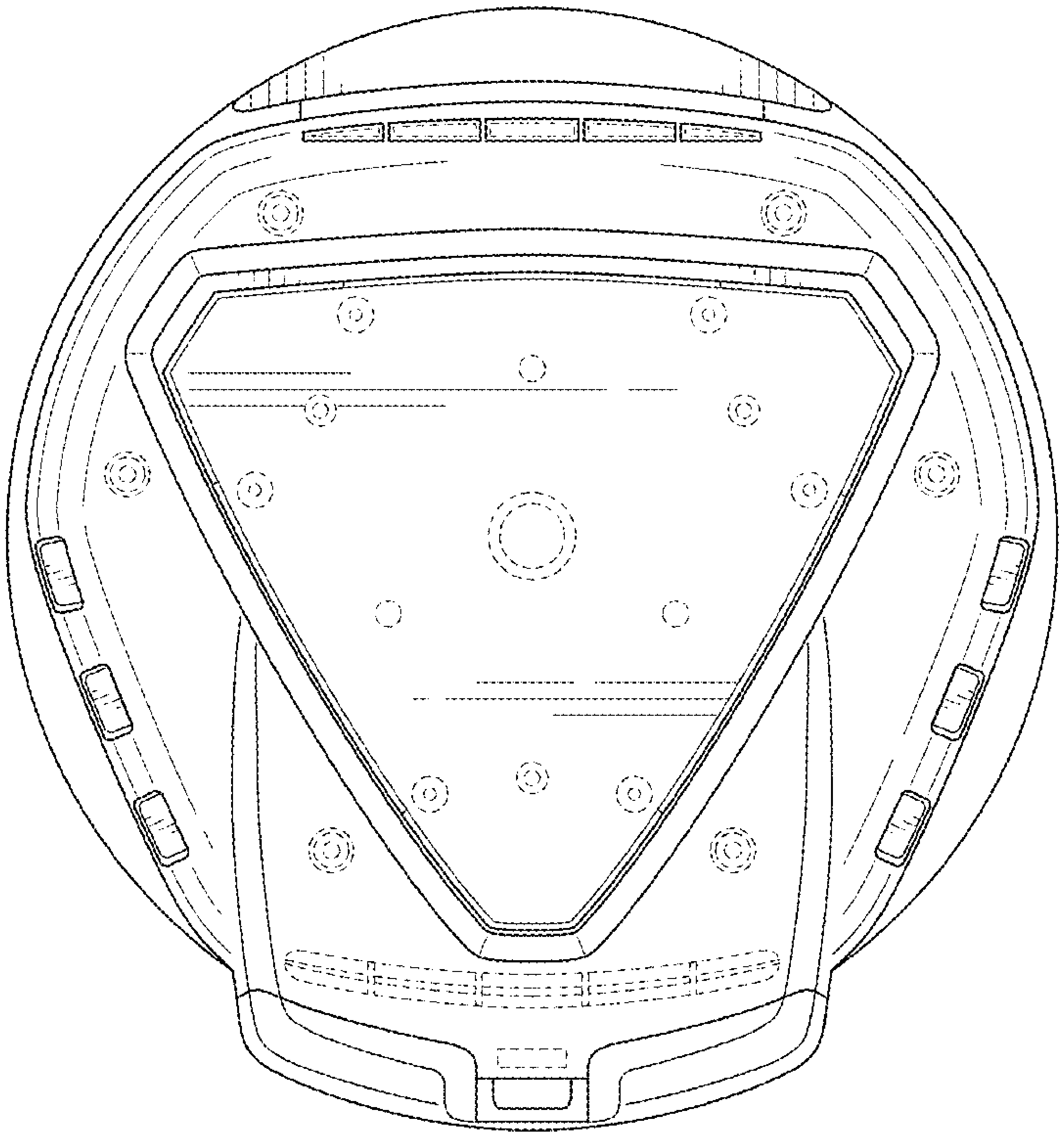


FIG. 7